

## STU7N60DM2

# N-channel 600 V, 0.78 Ω typ., 6 A MDmesh™ DM2 Power MOSFET in an IPAK package

Datasheet - production data

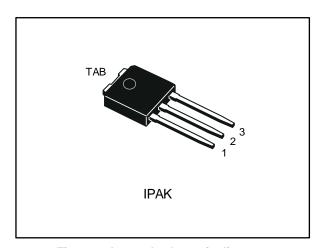
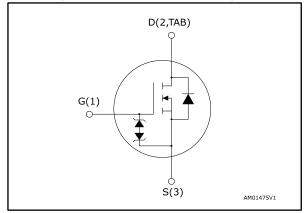


Figure 1: Internal schematic diagram



#### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	ΙD	Ртот
STU7N60DM2	600 V	0.90 Ω	6 A	60 W

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

### **Applications**

Switching applications

### **Description**

This high voltage N-channel Power MOSFET is part of the MDmesh  $^{\text{TM}}$  DM2 fast recovery diode series. It offers very low recovery charge (Q<sub>rr</sub>) and time (t<sub>rr</sub>) combined with low R<sub>DS(on)</sub>, rendering it suitable for the most demanding high efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

**Table 1: Device summary** 

Order code	Marking	Package	Packing
STU7N60DM2	7N60DM2	IPAK	Tube

Contents STU7N60DM2

# Contents

1	Electric	cal ratings	3
2	Electric	cal characteristics	4
	2.1	Electrical characteristics (curves)	6
3	Test cir	rcuits	8
4	Packag	e information	9
	4.1	IPAK package information	9
5	Revisio	on history	11

STU7N60DM2 Electrical ratings

# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>G</sub> s	Gate-source voltage	±25	V
1_	Drain current (continuous) at T <sub>case</sub> = 25 °C	6	۸
ID	Drain current (continuous) at T <sub>case</sub> = 100 °C	3.8	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed) 24		Α
P <sub>TOT</sub>	Total dissipation at T <sub>case</sub> = 25 °C 60		W
dv/dt <sup>(2)</sup>	Peak diode recovery voltage slope 50		V/ns
dv/dt <sup>(3)</sup>	MOSFET dv/dt ruggedness 50		V/IIS
T <sub>stg</sub>	Storage temperature range -55 to 150		°C
Tj	Operating junction temperature range	-55 (0 150	C

#### Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit	
R <sub>thj-case</sub>	Thermal resistance junction-case	2.08		
R <sub>thj-amb</sub>	Thermal resistance junction-ambient	100	°C/W	

**Table 4: Avalanche characteristics** 

Symbol	Parameter	Value	Unit
I <sub>AR</sub> <sup>(1)</sup>	Avalanche current, repetitive or not repetitive	1.5	Α
Eas <sup>(2)</sup>	Single pulse avalanche energy	160	mJ

#### Notes:

<sup>(1)</sup> Pulse width is limited by safe operating area.

 $<sup>^{(2)}</sup>$   $I_{SD} \leq 6$  A, di/dt=900 A/µs;  $V_{DS}$  peak <  $V_{(BR)DSS},$   $V_{DD}$  = 480 V.

 $<sup>^{(3)}</sup>$  V<sub>DS</sub>  $\leq 480$  V.

 $<sup>^{(1)}</sup>$  Pulse width limited by  $T_{jmax}$ .

 $<sup>^{(2)}</sup>$  Starting  $T_j$  = 25 °C,  $I_D$  =  $I_{AR},\,V_{DD}$  = 50 V.

Electrical characteristics STU7N60DM2

## 2 Electrical characteristics

(T<sub>case</sub> = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			٧
	Zoro goto voltago droin	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$			1	
IDSS	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V},$ $T_{case} = 125 \text{ °C} (1)$			100	μΑ
Igss	Gate-body leakage current	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = ±25 V			±5	μΑ
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	3.25	4	4.75	V
R <sub>DS(on)</sub>	Static drain-source on-resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 3 A		0.78	0.90	Ω

#### Notes:

Table 6: Dynamic

Symbol	Parameter	Test conditions		Тур.	Max.	Unit
Ciss	Input capacitance		-	324	-	
Coss	Output capacitance	V <sub>DS</sub> = 100 V, f = 1 MHz,	-	18	-	pF
C <sub>rss</sub>	Reverse transfer capacitance	$V_{GS} = 0 V$	-	2	1	ρı
Coss	Equivalent output capacitance	V <sub>DS</sub> = 0 to 480 V, V <sub>GS</sub> = 0 V	-	25	-	pF
Rg	Intrinsic gate resistance	f = 1 MHz, I <sub>D</sub> = 0 A	-	6	-	Ω
Qg	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 6 \text{ A},$	-	7.5	-	
Qgs	Gate-source charge	V <sub>GS</sub> = 0 to 10 V (see Figure 15: "Test circuit for	-	2.2	-	nC
$Q_{gd}$	Gate-drain charge	gate charge behavior")	-	3.2	-	

#### Notes:

**Table 7: Switching times** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 3 \text{ A R}_G = 4.7 \Omega,$	-	10	-	
t <sub>r</sub>	Rise time	$V_{GS} = 10 \text{ V}$ (see Figure 14: "Test circuit for		6	-	
t <sub>d(off)</sub>	Turn-off delay time	resistive load switching times"	-	12.6	-	ns
t <sub>f</sub>	Fall time	and Figure 19: "Switching time waveform")	1	22.6	1	



<sup>&</sup>lt;sup>(1)</sup>Defined by design, not subject to production test.

 $<sup>^{(1)}</sup>$  C<sub>oss eq.</sub> is defined as a constant equivalent capacitance giving the same charging time as C<sub>oss</sub> when V<sub>DS</sub> increases from 0 to 80% V<sub>DSS</sub>.

Table 8: Source-drain diode

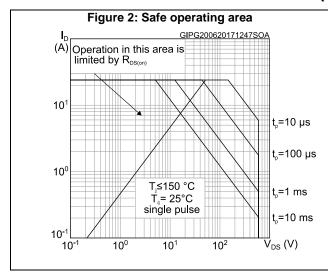
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		ı		6	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		24	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 6 A	ı		1.6	V
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 6 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s,}$	1	69		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}$ (see Figure 16: "Test circuit for	-	164		nC
I <sub>RRM</sub>	Reverse recovery current	inductive load switching and diode recovery times")	-	4.8		Α
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 6 A, di/dt = 100 A/µs,	-	144		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 \text{ °C}$ (see <i>Figure 16: "Test circuit for</i>	-	492		nC
I <sub>RRM</sub>	Reverse recovery current	inductive load switching and diode recovery times")	-	6.8		Α

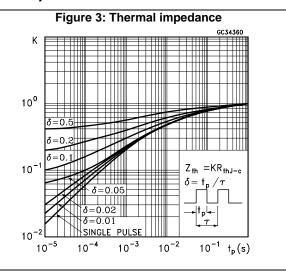
#### Notes:

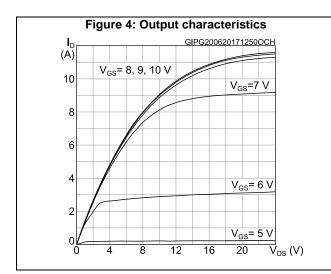
<sup>&</sup>lt;sup>(1)</sup> Pulse width is limited by safe operating area.

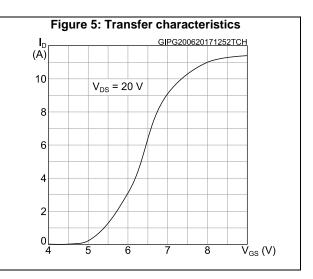
 $<sup>^{(2)}</sup>$  Pulse test: pulse duration = 300  $\mu s,$  duty cycle 1.5%.

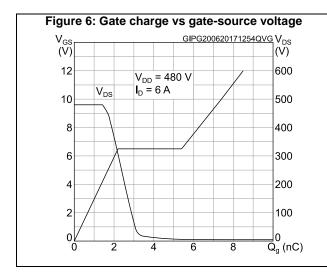
## 2.1 Electrical characteristics (curves)

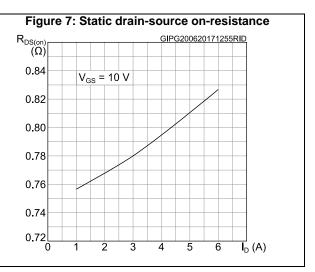










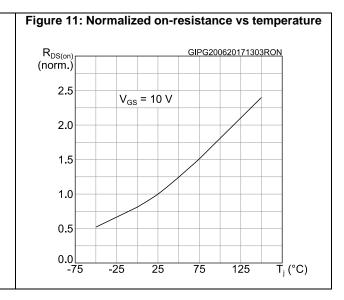


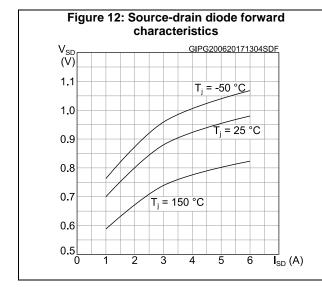
STU7N60DM2 Electrical characteristics

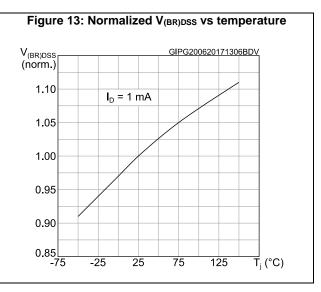
Figure 8: Capacitance variations GIPG200620171256CVR (pF)  $10^{3}$ C<sub>ISS</sub>  $10^{2}$ Coss 10<sup>1</sup> f = 1 MHz  $C_{\text{RSS}}$ 10<sup>0</sup>  $\vec{V}_{DS}(V)$ 10<sup>-1</sup>  $10^{0}$ 10<sup>1</sup>  $10^{2}$ 

E<sub>OSS</sub> (μJ) 2.4 2.0 1.6 1.2 0.8 0.4 0.0 0 100 200 300 400 500 600 V<sub>DS</sub> (V)

Figure 10: Normalized gate threshold voltage vs temperature V<sub>GS(th)</sub> (norm.) GIPG200620171302VTH  $I_D = 250 \, \mu A$ 1.1 1.0 0.9 8.0 0.7 -25 25 75 125  $\overline{\mathsf{T}}_{\mathsf{j}}\left(^{\mathsf{o}}\mathsf{C}\right)$ 







Test circuits STU7N60DM2

## 3 Test circuits

Figure 14: Test circuit for resistive load switching times

Figure 15: Test circuit for gate charge behavior

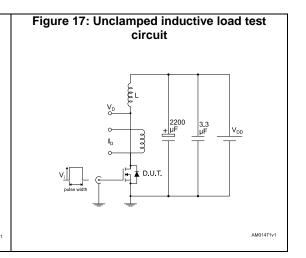
12 V 47 kΩ 100 nF 1 kΩ

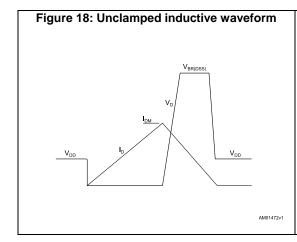
Vos 1 kΩ 1 kΩ

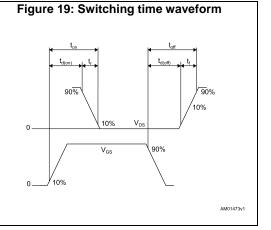
Vos 1 kΩ 1 kΩ

AM01466y1

Figure 16: Test circuit for inductive load switching and diode recovery times







# 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

## 4.1 IPAK package information

*L2* D b2 (3x) Н **b** (3x) A 1 *B5* 0068771\_IK\_typeA\_rev14 e 1-

Figure 20: IPAK (TO-251) type A package outline

Table 9: IPAK (TO-251) type A package mechanical data

Dim.		mm	
	Min.	Тур.	Max.
Α	2.20		2.40
A1	0.90		1.10
b	0.64		0.90
b2			0.95
b4	5.20		5.40
B5		0.30	
С	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
Е	6.40		6.60
е		2.28	
e1	4.40		4.60
Н		16.10	
L	9.00		9.40
L1	0.80		1.20
L2		0.80	1.00
V1		10°	

STU7N60DM2 Revision history

# 5 Revision history

Table 10: Document revision history

Date	Revision	Changes
20-Jun-2017	1	First release.

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